

GROUP	2125
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## U.S. PATENT DOCUMENTS

[illegible]

## FOREIGN PATENT DOCUMENTS

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**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)


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## INFORMATION DISCLOSURE CITATION

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Applicants: Paul J. Stewart et al.

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AWR	5,631,861	05/20/1997	Kramer			
CWP	5,792,031	08/11/1998	Alton			
AWR	5,793,382	08/11/1998	Yerazunis et al.			
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AWR	5,930,155	07/27/1999	Tohi et al.			
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AWR	6,036,345	03/14/2000	Jannette et al.			
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AWR	6,084,590	07/04/2000	Robotham et al.			

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

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AWR		Artificial Intelligence (Understanding Computers), by Time-Life Books, 1986, ISBN 0-8094-5675-3, pages 36-43.
		Juran on Quality by Design, by J.M. Juran, The Free Press, 1992, ISBN 0-02-916683-7, pages 406-427, and 462-467.
		The Computer Science and Engineering Handbook, by Allen B. Tucker, CRC Press, ISBN: 0-8493-2909-4, 1996, page 1954.

EXAMINER

Albert W. Paladini

ALBERT W. PALADINI

PATENT EXAMINER

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QW	6,253,167	06/26/2001	Matsuda et al.			
QW	6,273,724	08/14/2001	Roytman			
QW	2002/0000996 A1	01/03/2002	Trika			
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QW	2003/0134676 A1	07/17/2003	Kang			

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						YES	NO

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200-1453

SERIAL NO.

10/042,918

Applicants: Paul J. Stewart et al.

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JM	5,459,382	10/17/1995	Jacobus et al.	—	—	
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JM	6,262,738	07/17/2001	Gibson et al.	—	—	
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Or	2002/0163497 A1	11/07/2002	Cunningham et al.	—	—	

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Albert W. Paladino

ALBERT W. PALADINO  
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Paul Joseph Stewart et al.

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Am	5,119,309	06/02/1992	Cavendish et al.	—	—	
Am	5,179,644	201/12/1993	Chiyokura et al.	—	—	
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Am	5,504,845	04/02/1996	Vecchione	—	—	
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Am		Duane et al., "DOE/Opt: A System for Design of Experiments, Response Surface Modeling and Optimization Using Process and Device Simulation" 1993. pg.1-4.
		Chen et al., "A Real-Time, Interactive Method for Fast Modification of Large-Scale CAE mesh Models" 2000. pg. 1-8.
Am		Chen et al. IMF 1.0 User Manual Project No. AJ499 Ford Research Laboratory 10/26/1999. pg.1-14.

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